The Order–Disorder Transition of Stage-1 Graphite Fluoroarsenate Intercalation Compound: the Structure of C₁₆AsF₆ below 170 K

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Guinier–Simon X-ray diffraction data for the stage-1 graphite fluoroarsenate intercalation compound, $C_{16}AsF_6$, indicate that it undergoes an order–disorder transition at ca. 170 K and has the F-ligands of AsF_6 – anions nestled in adjacent three-fold sets of carbon-atom hexagons of the enclosing graphite layers with three-dimensional (3-D) ordering of the anions in the low-temperature phase.

Significant differences have been observed between the room temperature Debye–Scherrer (DS) powder diffraction pattern for the stage-1 graphite–AsF₅ intercalation compound, $C_8AsF_5^{1,2}$ (c-axis repeat distance, $I_c \approx 8.0$ Å) and that for the stage-1 compound, $C_{\sim 14}AsF_6$ (graphite hexafluoroarsenate).^{3–5} The typical diffraction patterns are shown in Fig. 1. The former is made by the reaction of graphite with AsF₅ and

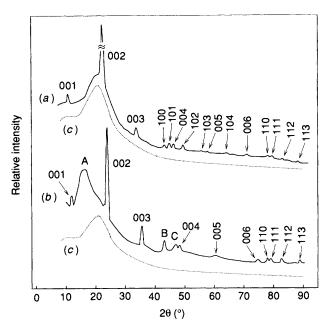


Fig. 1 Debye–Scherrer X-ray powder diffraction patterns (Cu-K α) of: (a) C₈AsF₅ ($I_c=8.0$ Å), (b) C₁₄AsF₆ ($I_c=7.6$ Å) and (c) quartz capillary background

the latter with AsF₅-F₂ or O₂AsF₆. The latter is characterized by the very small I_c (\approx 7.6 Å) and the unusual features, *i.e.* the appearance of a low angle halo [halo A in pattern (b) in Fig. 1] and two peaks (B and C), and the absence of (100) and (101) reflections. These features suggested3-5 that the F-ligands of AsF₆⁻ are nestled in contiguous three-fold sets of C-atom hexagons of the graphite. A model has been proposed^{3,4} in which staggered C-layers are randomly stacked (e.g. A|B-|A|C|B|..., where | denotes intercalate layer) with short-range ordering or domain structure of nestled AsF₆⁻ anions within each gallery. All the unusual features of the pattern for the $C_{\sim 14}$ AsF₆ sample with $I_c \simeq 7.6$ Å are explained by the nestling of AsF₆⁻. Ideally, the most dense arrangement of AsF₆⁻ has the composition C₁₄AsF₆ (see Fig. 2). However, the large anisotropic thermal parameters (U_{11}) for As and F atoms (0.25)and 0.50 Å², respectively) needed for the simulation had made the nestling of AsF₆⁻ less convincing. In order to obtain more definite evidence for the nestling, Guinier-Simon X-ray diffraction photographs⁶ were obtained for the stage-1 graphite fluoroarsenate intercalation compound, C_xAsF₆, in the temperature ranges of 300-390 K4 and 290-80 K. We report here the results of the 290-80 K photograph.

The Guinier–Simon photograph was obtained for a sample with the nominal composition of $C_{18.9}AsF_6$ (see below) using $Cu-K\alpha_1$ radiation in the temperature range of 290–80 K. The sample was prepared by the reaction of graphite powder (Union Carbide SP-1) with AsF_5 and F_2 . The reaction was run for 6 h at room temperature and the composition was determined by gravimetry assuming the formula C_xAsF_6 . Previous studies^{3.4} had demonstrated that, if the I_c -distances of samples prepared in this way were less than ca. 7.6 Å, their compositions were $C_{\sim 14}AsF_{6.0}$. In the present work some loss of graphite and/or product from the reaction cell was observed during the manipulation. Therefore, the composition of the sample should be C_xAsF_6 (14 $\leq x \leq$ 18.9). The diffraction

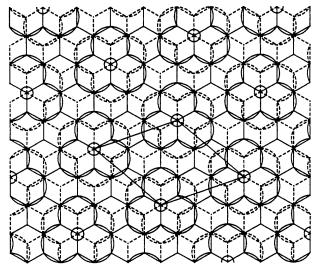


Fig. 2 In-plane structure of C₁₄AsF₆

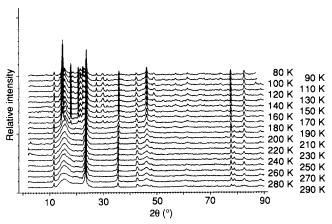


Fig. 3 Temperature dependence of X-ray powder diffraction pattern of $C_x As F_6$ (14 < x < 18.9) between 80–290 K

patterns read by an image scanner⁷ at intervals of 10 K are shown in Fig. 3.

As the temperature is lowered, super-lattice reflections appear, indicating an order-disorder transition in the AsF₆⁻ arrangement and, consequently, in the carbon layer stacking sequence at ca. 170 K. The reflection pattern at lower temperature has been satisfactorily simulated by a nestled C₁₆AsF₆ model. The in-plane arrangement of AsF₆⁻ for the model is shown in Fig. 4(a). The pseudo-face-centred orthorhombic arangement of AsF₆⁻ requires the carbon-layer stacking sequence to be A|B|A|B|, [see Fig. 4(b)]. The space group is C2/m, and the lattice constants are $a = 4 \times 10^{-3}$ $a(graphite) = 9.8 \text{ Å}, b = 2\sqrt{3} \times a_g = 8.5 \text{ Å}, c = 2 \times I_c = 14.9$ Å and $\beta = 90^{\circ}$ at 90 K. The observed and calculated diffraction patterns at 90 K are shown Fig. 5. The fit is satisfactory, although there are some discrepancies: (i) some of the observed lower angle reflections do not appear in the simulated pattern, (ii) the relative intensities of some of the reflections are reversed, (iii) in the simulated pattern most of the super-lattice reflections are much stronger than the others, and (iv) in the observed pattern the graphite (100) reflection is shifted towards a higher angle. These discrepancies indicate that even at 90 K there exist some disorders in the 3-D arrangement of AsF₆⁻ and in the carbon layer stacking

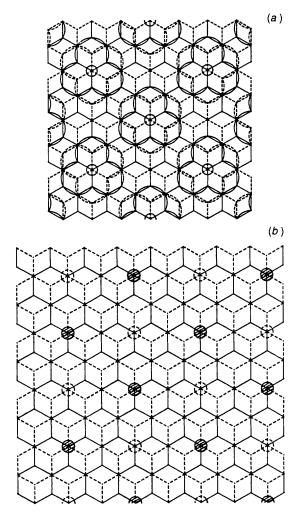


Fig. 4 Structure of $C_{16}AsF_6$: (a) in-plane structure of $C_{16}AsF_6$ (nestling of AsF_6 - is shown) and (b) positions of As-atoms (open and hatched circles belong to different galleries)

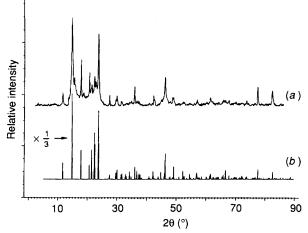


Fig. 5 (a) Observed and (b) calculated X-ray diffraction patterns for $C_{16}AsF_6$ at 90 K

sequence.^{3,4} However, the pattern on the whole is simulated well by the $C_{16}AsF_6$ model.

The nestling of AsF_6^- is geometrically justified as follows. The As-F distance in the AsF_6^- ion is ca. $\sqrt{3}$ Å.8.9 Then, assuming that the ion is a regular octahedron with $d(As-F) = \sqrt{3}$ Å. the neighbouring F-F distance is $\sqrt{6}$ Å, which is essentially the same as the lattice constant, a, of graphite. In

 $[\]dagger$ In taking the Guinier–Simon photographs no internal standard was used to aid precise lattice constant determination. The second decimal digits in Å were rounded.

the present model, the F-atoms are placed at the centre of the carbon hexagons in the ab-projection and 1.0 Å above and below the central As-atom along the c-axis direction. The thermal parameters were not used, i.e. they were set equal to zero.

Some comments need to refer to the composition of the sample. Although the ideal composition of the ordered structure is $C_{16}AsF_{6}$,‡ the disordered phase need not have the exact composition $C_{16}AsF_{6}$ to produce the observed diffraction pattern.§ It is reasonable to assume that, as the temperature is lowered, the ordered phase $C_{16}AsF_{6}$ 'crystallizes out' in the bulk of the sample leaving the rest of the sample having a composition different from $C_{16}AsF_{6}$, thus, allowing the overall composition to be different from $C_{16}AsF_{6}$. This is probably one of the reasons why some disorders persist even in the low-temperature phase.

‡ Not only the composition but also the formulation, $C_{16}^+AsF_6^-$, warrant some comments. Chemical analyses done on the vacuum stable samples made by the reaction of graphite with AsF_5 , $AsF_5^-F_2$, or O_2AsF_6 have shown that their compositions are $C_xAsF_{6.0}$ with x varying between 13-20 (refs. 3 and 4). Therefore, although the physical ionic salt limit (charge transfer limit) in graphite–fluoroarsenate can be C_{20}^+ (J. W. Milliken and J. E. Fischer, J. Chem. Phys., 1983, 78, 5800), the chemical formulation, $C_{16}^+AsF_6^-$, should be valid. The present structural study also supports this.

§ When the compositions of samples are $C_x \text{AsF}_y$ ($x < 14, 5 \le y \le 6$), then the I_c -distances are ca. 8.0 Å, and their diffraction patterns look essentially the same [see Fig. 1(a)].

Apparently, strong Coulombic interaction among AsF_6^- ions controls the structure of $C_{16}AsF_6$, which was expected but not clearly observed in $C_{8n}AsF_5$. This interaction probably renders the $C_{14}AsF_6$ structure, 4.4 which has the most dense arrangement of nestled AsF_6^- ions, unstable, since a torque is exerted on each AsF_6^- by the electric field produced by the other AsF_6^- ions in the same gallery (see Fig. 2).

other AsF₆⁻ ions in the same gallery (see Fig. 2).

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